Features

- Industry-standard Architecture
- 12 ns Maximum Pin-to-pin Delay
- Zero Power 25 μA Maximum Standby Power (Input Transition Detection)
- CMOS and TTL Compatible Inputs and Outputs
- Advanced Electrically-erasableTechnology
 - Reprogrammable
 - 100% Tested
- Latch Feature Holds Inputs to Previous Logic State
- High-reliability CMOS Process
 - 20 Year Data Retention
 - 100 Erase/Write Cycles
 - 2,000V ESD Protection
 - 200 mA Latchup Immunity
- Commercial and Industrial Temperature Ranges
- Dual-in-line and Surface Mount Standard Pinouts
- PCI Compliant
- Green Package Options (Pb/Halide-free/RoHS Compliant) Available

1. Desscription

The ATF22V10CZ/CQZ is a high-performance CMOS (electrically-erasable) programmable logic device (PLD) which utilizes Atmel's proven electrically-erasable Flash memory technology. Speeds down to 12 ns with zero standby power dissipation are offered. All speed ranges are specified over the full 5V $\pm 10\%$ range for industrial temperature ranges; 5V $\pm 5\%$ for commercial range 5-volt devices. The ATF22V10CZ/CQZ provides a low voltage and edge-sensing "zero" power CMOS PLD solution with "zero" standby power (5 μA typical). The ATF22V10CZ/CQZ provides a "zero" power CMOS PLD solution with 5V operating voltages, powering down automatically to the zero power-mode through Atmel's patented Input Transition Detection (ITD) circuitry when the device is idle, offering "zero" (25 μA worst case) standby power. This feature allows the user to manage total system power to meet specific application requirements and enhance reliability. Pin "keeper" circuits on input and output pins eliminate static power consumed by pull-up resistors. The "CQZ" combines the low high-frequency I_{CC} of the "Q" design with the "Z" feature.

The ATF22V10CZ/CQZ incorporates a superset of the generic architectures, which allows direct replacement of the 22V10 family and most 24-pin combinatorial PLDs. Ten outputs are each allocated 8 to 16 product terms. Three different modes of operation, configured automatically with software, allow highly complex logic functions to be realized.



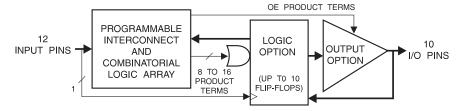
Highperformance EE PLD

ATF22V10CZ ATF22V10CQZ





Figure 1-1. Block Diagram



2. Pin Configurations

Table 2-1. Pin Configurations (All Pinouts Top View)

Pin Name	Function
CLK	Clock
IN	Logic Inputs
I/O	Bi-directional Buffers
VCC	+5V Supply

Figure 2-1. TSSOP

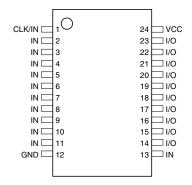
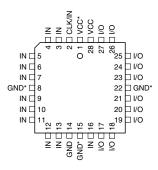


Figure 2-2. DIP/SOIC



Figure 2-3. PLCC



Note: For PLCC, P1, P8, P15 and P22 can be left unconnected. For superior performance, connect VCC to pin 1 and GND to 8, 15, and 22.

3. Absolute Maximum Ratings*

Temperature Under Bias40°C to +85°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground2.0V to +7.0V ⁽¹⁾
Voltage on Input Pins with Respect to Ground During Programming2.0V to +14.0V ⁽¹⁾
Programming Voltage with Respect to Ground2.0V to +14.0V ⁽¹⁾

*NOTICE:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1

Minimum voltage is -0.6V DC, which may undershoot to -2.0V for pulses of less than 20 ns.
 Maximum output pin voltage is V_{CC} + 0.75V DC, which may overshoot to 7.0V for pulses of less than 20 ns.

4. DC and AC Operating Conditions

	Commercial	Industrial
Operating Temperature (Ambient)	0°C - 70°C	-40°C - 85°C
V _{CC} Power Supply	5V ± 5%	5V ± 10%



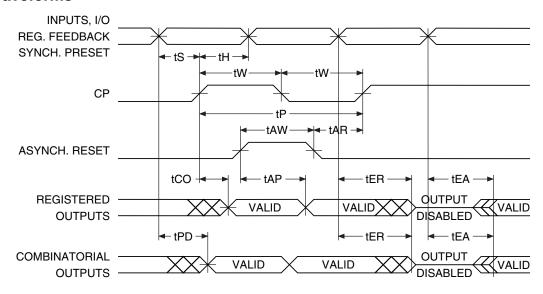


4.1 DC Characteristics

Symbol	Parameter	Condition			Min	Тур	Max	Units
I _{IL}	Input or I/O Low Leakage Current	$0 \le V_{IN} \le V_{IL} (Max)$	$0 \le V_{IN} \le V_{IL} (Max)$ $3.5 \le V_{IN} \le V_{CC}$				-10	μA
I _{IH}	Input or I/O High Leakage Current	$3.5 \le V_{IN} \le V_{CC}$					10	μΑ
			CZ-12, 15	Com		90	150	mA
	Clocked Power	V _{CC} = Max	CZ-15	Ind		90	180	mA
I _{CC}	Supply Current	Outputs Open, f = 15 MHz	CQZ-20	Com		40	60	mA
			CQZ-20	Ind		40	80	mA
	Power Supply Current, Standby		CZ-12, 15	Com		5	25	μΑ
		V _{CC} = Max V _{IN} = MAX Outputs Open	CZ-15	Ind		5	50	μΑ
I _{SB}			CQZ-20	Com		5	25	μΑ
			CQZ-20	Ind		5	50	μΑ
I _{OS} ⁽¹⁾	Output Short Circuit Current	V _{OUT} = 0.5V	V _{OUT} = 0.5V				-130	mA
V _{IL}	Input Low Voltage	·			-0.5		0.8	V
V _{IH}	Input High Voltage						V _{CC} + 0.75	V
V _{OL}	Output Low Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{CC} = \text{Min},$ $I_{OL} = 16 \text{ mA}$					0.5	V
V _{OH}	Output High Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{CCIO} = \text{Min},$ $I_{OH} = -4.0 \text{ mA}$		2.4			V	

Note: 1. Not more than one output at a time should be shorted. Duration of short circuit test should not exceed 30 sec.

4.2 AC Waveforms



4.3 AC Characteristics⁽¹⁾

		-	12	_	15	-2	20	
Symbol	Parameter	Min	Max	Min	Max	Min	Max	Units
t _{PD}	Input or Feedback to Non-registered Output	3	12	3	15	3	20	ns
t _{CF}	Clock to Feedback		6		4.5		8	ns
t _{co}	Clock to Output	2	8	2	8	2	12	ns
t _S	Input or Feedback Setup Time	10		10		14		ns
t _H	Input Hold Time	0		0		0		ns
t _W	Clock Width	6		6		10		ns
f _{MAX}	External Feedback $1/(t_S + t_{CO})$ Internal Feedback $1/(t_S + t_{CF})$ No Feedback $1/(t_P)$		55.5 62 83.3		55.5 69 83.3	38.5 45.5 50.0		MHz MHz MHz
t _{EA}	Input to Output Enable - Product Term	3	12	3	15	3	20	ns
t _{ER}	Input to Output Disable - Product Term	2	15	3	15	3	20	ns
t _{PZX}	OE Pin to Output Enable	2	12	2	15	2	20	ns
t _{PXZ}	OE Pin to Output Disable	2	15	2	15	2	20	ns
t _{AP}	Input or I/O to Asynchronous Reset of Register	3	10	3	15	3	22	ns
t _{SP}	Setup Time, Synchronous Preset	10		10		14		ns
t _{AW}	Asynchronous Reset Width	7		8		20		ns
t _{AR}	Asynchronous Reset Recovery Time	5		6		20		ns
t _{SPR}	Synchronous Preset to Clock Recovery Time	10		10		14		ns

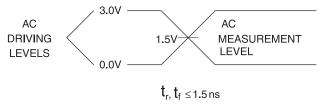
Note: 1. See ordering information for valid part numbers.



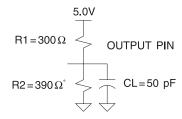


4.4 Input Test Waveforms

4.4.1 Input Test Waveforms and Measurement Levels



4.4.2 Output Test Loads



Note: Similar competitors devices are specified with slightly different loads. These load differences may affect output signals' delay and slew rate. Atmel devices are tested with sufficient margins to meet compatible device specification conditions.

4.5 Pin Capacitance

Table 4-1. Pin Capacitance (f = 1 MHz, T = $25C^{(1)}$)

	Тур	Max	Units	Conditions
C _{IN}	8	10	pF	V _{IN} = 0V; f = 1.0 MHz
C _{I/O}	8	10	pF	V _{OUT} = 0V; f = 1.0 MHz

Note:

 Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

4.6 Power-up Reset

The registers in the ATF22V10CZ/CQZ are designed to reset during power-up. At a point delayed slightly from V_{CC} crossing V_{RST} , all registers will be reset to the low state. The output state will depend on the polarity of the buffer.

This feature is critical for state machine initialization. However, due to the asynchronous nature of reset and the uncertainty of how V_{CC} actually rises in the system, the following conditions are required:

- 1. The V_{CC} rise must be monotonic and start below 0.7V.
- 2. The clock must remain stable during T_{PR}.
- 3. After T_{PR} occurs, all input and feedback setup times must be met before driving the clock pin high.

4.7 Preload of Register Outputs

The ATF22V10CZ/CQZ's registers are provided with circuitry to allow loading of each register with either a high or a low. This feature will simplify testing since any state can be forced into the registers to control test sequencing. A JEDEC file with preload is generated when a source file

6

with vectors is compiled. Once downloaded, the JEDEC file preload sequence will be done automatically by most of the approved programmers after the programming.

5. Electronic Signature Word

There are 64 bits of programmable memory that are always available to the user, even if the device is secured. These bits can be used for user-specific data.

6. Security Fuse Usage

A single fuse is provided to prevent unauthorized copying of the ATF22V10CZ/CQZ fuse patterns. Once programmed, fuse verify and preload are inhibited. However, the 64-bit User Signature remains accessible. The security fuse should be programmed last, as its effect is immediate.

7. Programming/Erasing

Programming/erasing is performed using standard PLD programmers. See CMOS PLD Programming Hardware & Software Support for information on software/programming.

Figure 7-1. Programming/Erasing Timing

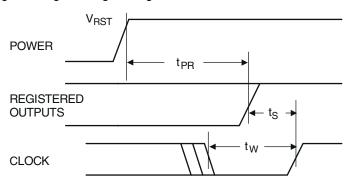


Table 7-1. Programming/Erasing

Parameter	Description	Тур	Max	Units
T _{PR}	Power-up Reset Time	600	1000	ns
V _{RST}	Power-up Reset Voltage	3.8	4.5	V

8. Input and I/O Pull-ups

All ATF22V10CZ/CQZ family members have internal input and I/O pin-keeper circuits. Therefore, whenever inputs or I/Os are not being driven externally, they will maintain their last driven state. This ensures that all logic array inputs and device outputs are at known states. These are relatively weak active circuits that can be easily overridden by TTL-compatible drivers (see input and I/O diagrams below).



Figure 8-1. Input Diagram

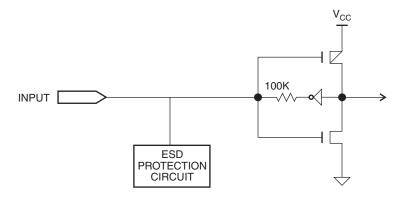
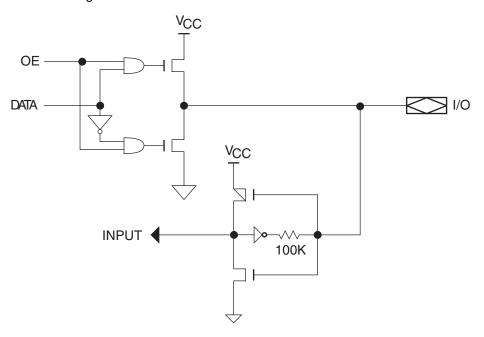


Figure 8-2. I/O Diagram



9. Compiler Mode Selection

 Table 9-1.
 Compiler Mode Selection

	PAL Mode (5828 Fuses)	GAL Mode (5892 Fuses)
Synario	ATF22V10C (DIP) ATF22V10C (PLCC)	ATF22V10C DIP (UES) ATF22V10C PLCC (UES)
WINCUPL	P22V10 P22V10LCC	G22V10 G22V10LCC

10. Functional Logic Diagram Description

The Functional Logic Diagram describes the ATF22V10CZ/CQZ architecture.

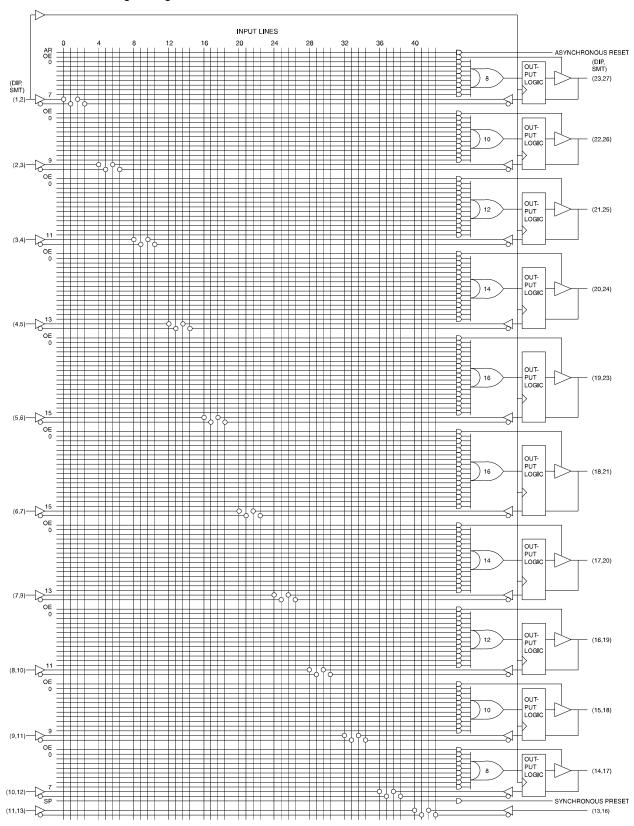
The ATF22V10CZ/CQZ has 12 inputs and 10 I/O macrocells. Each macrocell can be configured into one of four output configurations: active high/low, registered/combinatorial output. The universal architecture of the ATF22V10CZ/CQZ can be programmed to emulate most 24-pin PAL devices.

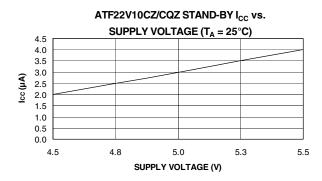
Unused product terms are automatically disabled by the compiler to decrease power consumption. A security fuse, when programmed, protects the contents of the ATF22V10CZ/CQZ. Eight bytes (64 fuses) of User Signature are accessible to the user for purposes such as storing project name, part number, revision or date. The User Signature is accessible regardless of the state of the security fuse.

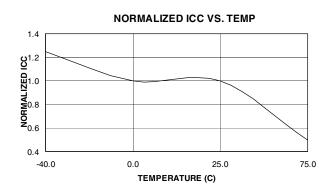


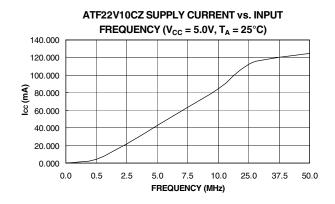


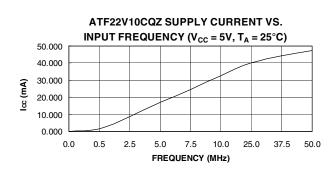
Figure 10-1. Functional Logic Diagram

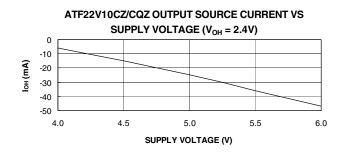


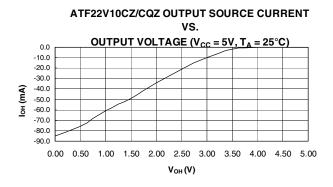


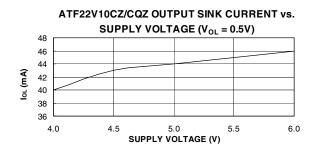


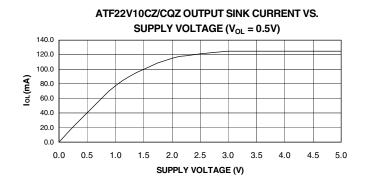






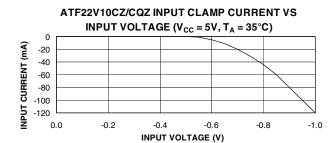


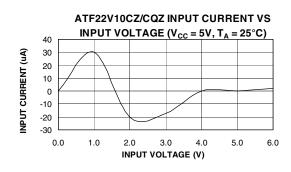


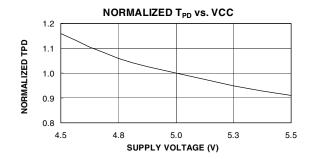


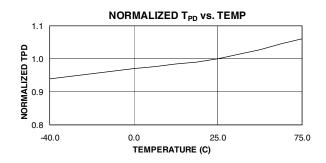


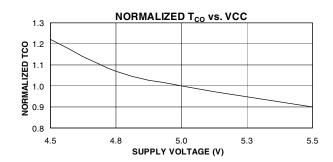


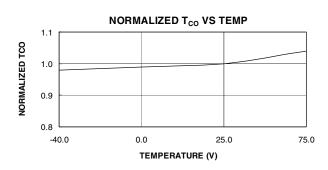


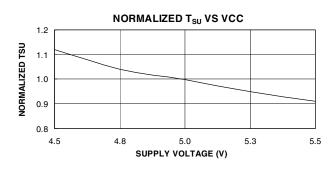


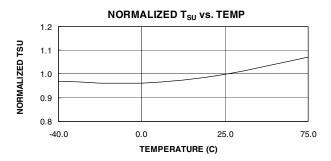


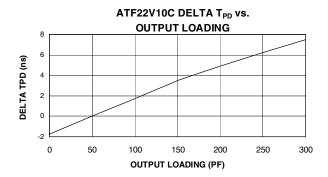


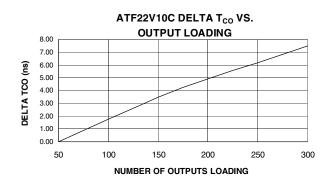


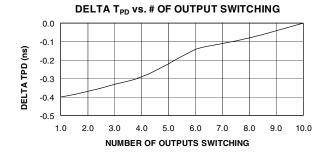


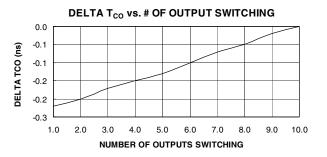














11. Ordering Information

11.1 Standard Package Options

		_			
t _{PD}	t _s	t _{co}			
(ns)	(ns)	(ns)	Ordering Code	Package	Operation Range
			ATF22V10CZ-12JC	28J	
12	10	8	ATF22V10CZ-12PC	24P3	Commercial
'-	10		ATF22V10CZ-12SC	24S	(0°C to 70°C)
			ATF22V10CZ-12XC	24X	
			ATF22V10CZ-15JC	28J	
			ATF22V10CZ-15PC	24P3	Commercial
			ATF22V10CZ-15SC	24S	(0°C to 70°C)
15	15 4.5	4.5 8	ATF22V10CZ-15XC	24X	,
15			ATF22V10CZ-15JI	28J	
			ATF22V10CZ-15PI	24P3	Industrial
			ATF22V10CZ-15SI	24S	(-40°C to +85°C)
			ATF22V10CZ-15XI	24X	,
			ATF22V10CQZ-20JC	28J	Commercial
			ATF22V10CQZ-20PC	24P3	
			ATF22V10CQZ-20SC	24S	(0°C to 70°C)
20	1.4	12	ATF22V10CQZ-20XC	24X	
20	20 14 1	12	ATF22V10CQZ-20JI	28J	
			ATF22V10CQZ-20PI	24P3	Industrial
			ATF22V10CQZ-20SI	24S	(-40°C to +85°C)
			ATF22V10CQZ-20XI	24X	,

11.2 ATF22V10CQZ Green Package Options (Pb/Halide-free/RoHS Compliant)

t _{PD} (ns)	t _s (ns)	t _{co} (ns)	Ordering Code	Package	Operation Range
20	14	12	ATF22V10CQZ-20JU ATF22V10CQZ-20PU ATF22V10CQZ-20SU ATF22V10CQZ-20XU	28J 24P3 24S 24X	Industrial (-40°C to +85°C)

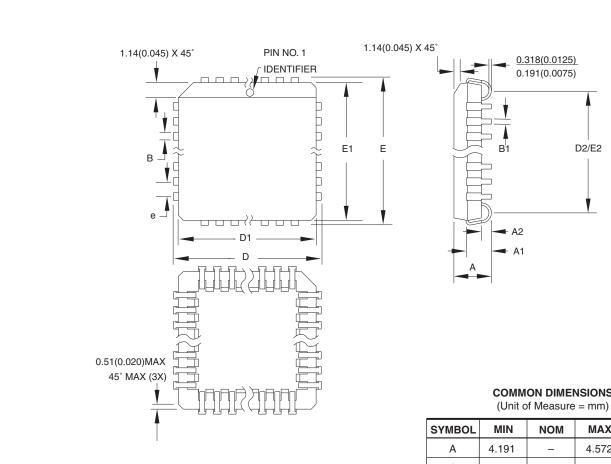
11.3 Using "C" Product for Industrial

To use commercial product for Industrial temperature ranges, down-grade one speed grade from the "I" to the "C" device (7 ns "C" = 10 ns "I") and de-rate power by 30%.

	Package Type				
28J	28-lead, Plastic J-leaded Chip Carrier (PLCC)				
24P3	24-pin, 0.300", Plastic Dual Inline Package (PDIP)				
24S	24-lead, 0.300" Wide, Plastic Gull-Wing Small Outline (SOIC)				
24X	24-lead, 4.4 mm Wide, Plastic Thin Shrink Small Outline (TSSOP)				

12. Packaging Information

12.1 **28J - PLCC**



Notes:

- 1. This package conforms to JEDEC reference MS-018, Variation AB.
- 2. Dimensions D1 and E1 do not include mold protrusion. Allowable protrusion is .010"(0.254 mm) per side. Dimension D1 and E1 include mold mismatch and are measured at the extreme material condition at the upper or lower parting line.
- 3. Lead coplanarity is 0.004" (0.102 mm) maximum.

COMMON	DIMENSIONS
/I Init of NA	

MAX NOTE 4.572 Α1 2.286 3.048 0.508 _ A2 12.319 12.573 D 11.430 D1 11.582 Note 2 Ε 12.319 12.573 11.430 E1 11.582 Note 2 D2/E2 9.906 10.922 В 0.660 0.813 В1 0.330 0.533 1.270 TYP е

10/04/01

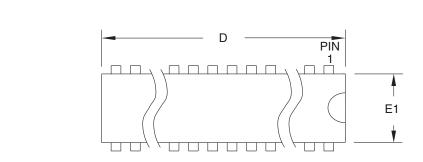
IIILE				
28J , 28-lead,	Plastic J-leaded	Chip	Carrier (P	LCC)

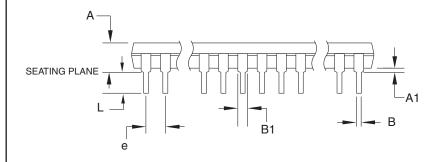
DRAWING NO.	REV	
28J	В	

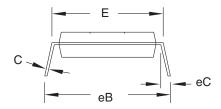




12.2 24P3 - PDIP







Notes:

- 1. This package conforms to JEDEC reference MS-001, Variation AF.
- Dimensions D and E1 do not include mold Flash or Protrusion. Mold Flash or Protrusion shall not exceed 0.25 mm (0.010").

COMMON DIMENSIONS

(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
Α	_	_	5.334	
A1	0.381		_	
D	31.623	_	32.131	Note 2
E	7.620	_	8.255	
E1	6.096	-	7.112	Note 2
В	0.356	_	0.559	
B1	1.270	-	1.651	
L	2.921	_	3.810	
С	0.203	-	0.356	
eB	_	_	10.922	
eC	0.000	_	1.524	
е	2.540 TYP			

6/1/04

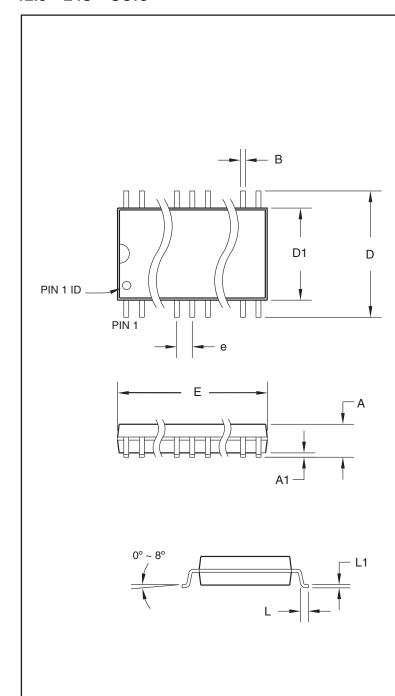
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2325 Orchard Parkway San Jose, CA 95131

TITLE	
24P3,	24-lead (0.300"/7.62 mm Wide) Plastic Dual
Inline	Package (PDIP)

DRAWING NO. REV. 24P3 D

12.3 24S - SOIC



COMMON DIMENSIONS

(Unit of Measure = mm)

MIN	NOM	MAX	NOTE
_	_	2.65	
0.10	-	0.30	
10.00	_	10.65	
7.40	_	7.60	
15.20	_	15.60	
0.33	_	0.51	
0.40	_	1.27	
0.23	_	0.32	
1.27 BSC			
	- 0.10 10.00 7.40 15.20 0.33 0.40	0.10 - 10.00 - 7.40 - 15.20 - 0.33 - 0.40 - 0.23 -	- - 2.65 0.10 - 0.30 10.00 - 10.65 7.40 - 7.60 15.20 - 15.60 0.33 - 0.51 0.40 - 1.27 0.23 - 0.32

06/17/2002

В

2325 Orchard Parkway San Jose, CA 95131

TITLE

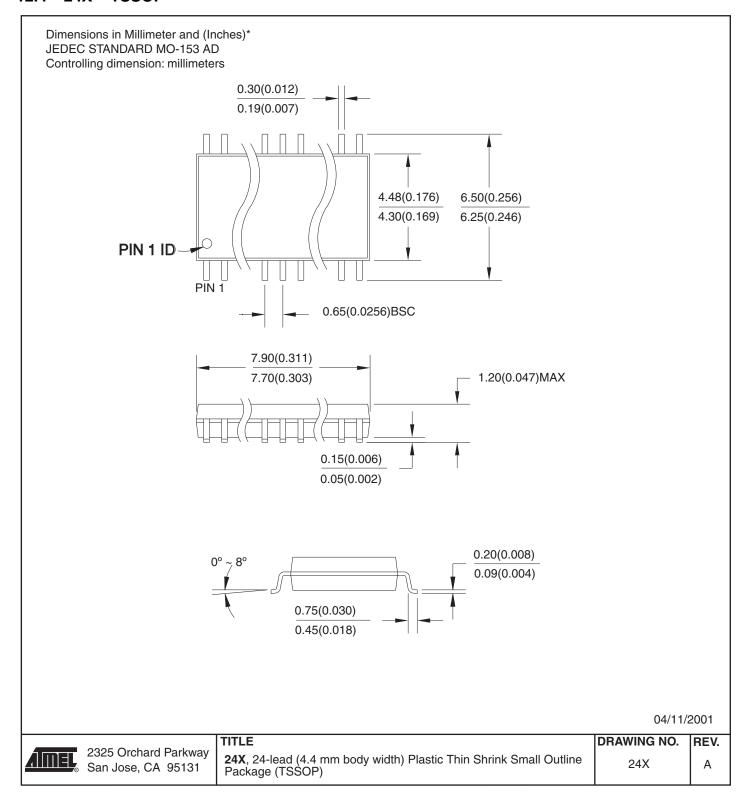
24S, 24-lead (0.300" body) Plastic Gull Wing Small Outline (SOIC)

DRAWING NO. REV.

24S



12.4 24X - TSSOP



13. Revision History

Version No./Release Date	History
Revision I – November 2005	Added Green Package options





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